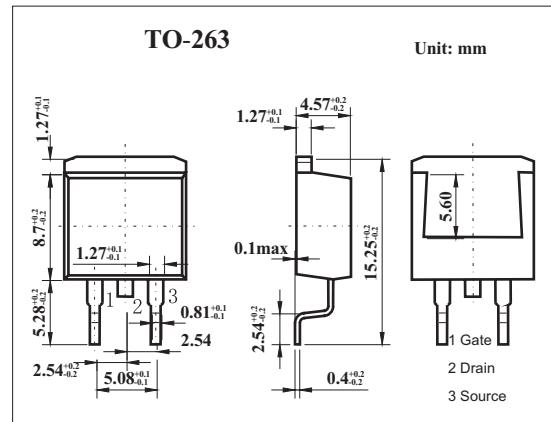
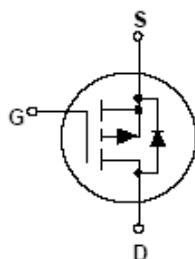


P-Channel 2.5V Specified Enhancement Mode Field Effect Transistor

KDB4020P(FDB4020P)

■ Features

- -16 A, -20 V. $R_{DS(on)} = 0.08 \Omega$ @ $V_{GS} = -4.5$ V
 $R_{DS(on)} = 0.11 \Omega$ @ $V_{GS} = -2.5$ V.
- Critical DC electrical parameters specified at elevated temperature.
- High density cell design for extremely low $R_{DS(on)}$.



■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain to source voltage	V_{DSS}	-20	V
Gate to source voltage	V_{GSS}	± 8	V
Drain current $T_c=25^\circ\text{C}$	I_D	-16	A
Drain current-pulsed	I_{DP}	-48	A
Power dissipation Derate above 25°C	P_D	37.5 0.25	W W/ $^\circ\text{C}$
Thermal Resistance, Junction-to- Case	$R_{\theta JC}$	4	$^\circ\text{C}/\text{W}$
Thermal Resistance Junction to Ambient	$R_{\theta JA}$	40	$^\circ\text{C}/\text{W}$
Channel temperature	T_{ch}	175	$^\circ\text{C}$
Storage temperature	T_{stg}	-55 to +175	$^\circ\text{C}$

KDB4020P(FDB4020P)■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain to source breakdown voltage	V_{DSS}	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
Drain cut-off current	I_{DSS}	$V_{DS}=-16\text{V}, V_{GS}=0, T_c=25^\circ\text{C}$			-1	μA
Gate leakage current	I_{GSS}	$V_{GS}=\pm 8\text{V}, V_{GS}=0\text{V}$			± 100	nA
Gate threshold voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.4	-0.58	-1	V
Drain to source on-state resistance	$R_{DS(on)}$	$V_{GS}=-4.5\text{V}, I_D=-8\text{A}$		0.068	0.08	Ω
		$V_{GS}=-4.5\text{V}, I_D=-8\text{A}, T_J=125^\circ\text{C}$		0.098	0.13	
		$V_{GS}=-2.5\text{V}, I_D=-7\text{A}$		0.096	0.110	
On-State Drain Current	$I_{D(on)}$	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-20			A
Forward Transconductance	g_{FS}	$V_{DS} = -5 \text{ V}, I_D = -8 \text{ A}$		14		S
Input capacitance	C_{iss}	$V_{DS}=-10\text{V}, V_{GS}=0, f=1\text{MHZ}$		665		pF
Output capacitance	C_{oss}			270		pF
Reverse transfer capacitance	C_{rss}			70		pF
Total Gate Charge	Q_g	$V_{DS} = -5 \text{ V},$		9.5	13	nC
Gate-Source Charge	Q_{gs}	$I_D = -16 \text{ A}, V_{GS} = -4.5 \text{ V}^*$		1.3		nC
Gate-Drain Charge	Q_{gd}			2.2		nC
Turn-on delay time	t_{on}	$V_{DD} = -5 \text{ V}, I_D = -1 \text{ A},$ $V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega^*$		8	16	ns
Rise time	t_r			24	38	ns
Turn-off delay time	t_{off}			50	80	ns
Fall time	t_f			29	45	ns
Maximum Continuous Drain-Source Diode Forward Current	I_S				-16	A
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}				-48	A
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS} = 0 \text{ V}, I_S = -16 \text{ A}^*$			-1.2	V

* Pulse Test: Pulse Width $\leqslant 300 \mu\text{s}$, Duty Cycle $\leqslant 2.0\%$